OIPE
JUL 1 2 2004
JC113
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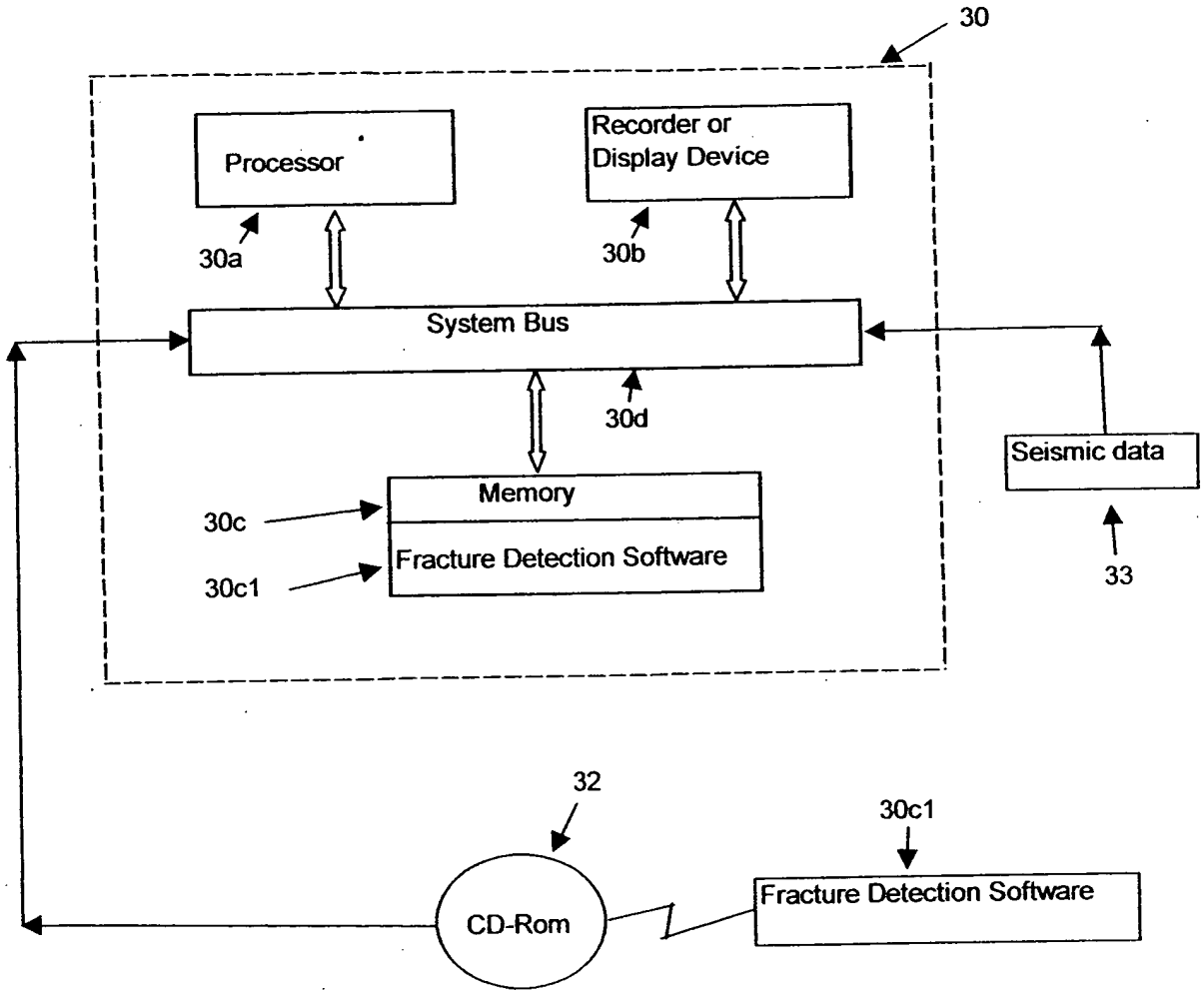

FIG 1

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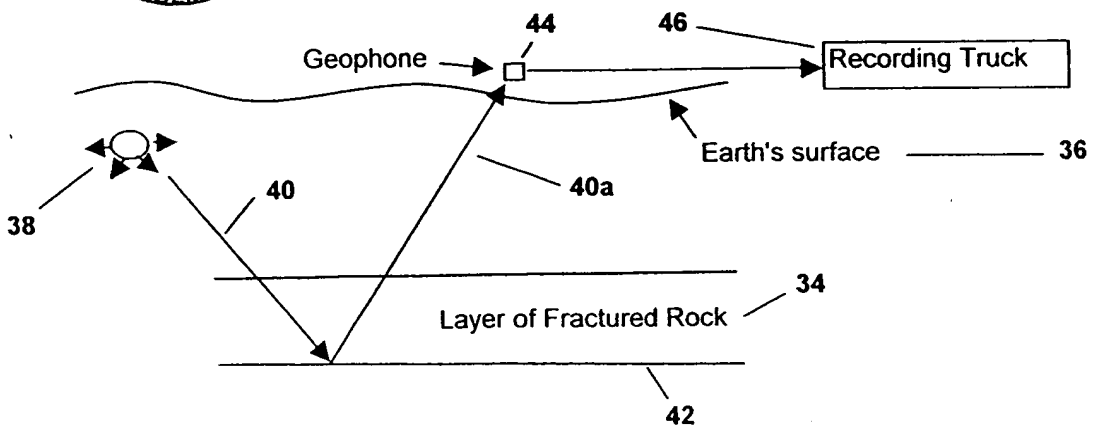

FIG 2

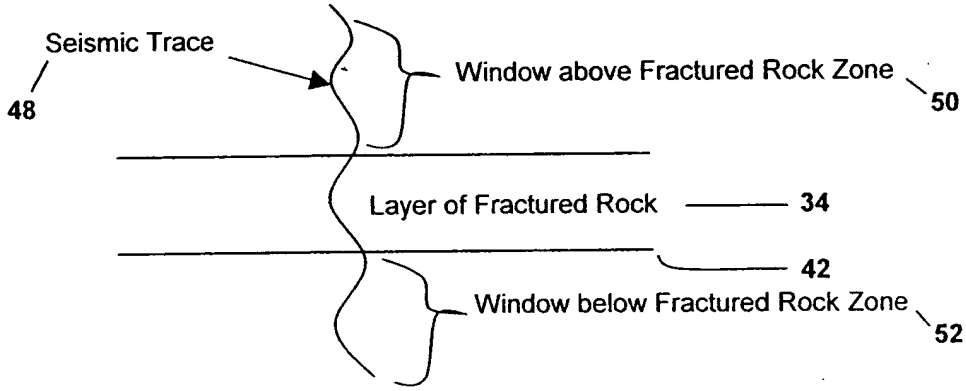

FIG 3

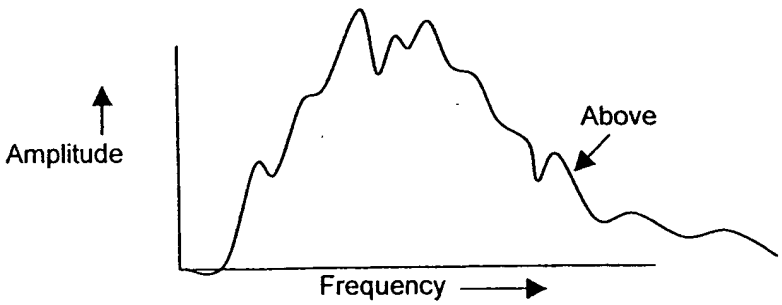

FIG 4

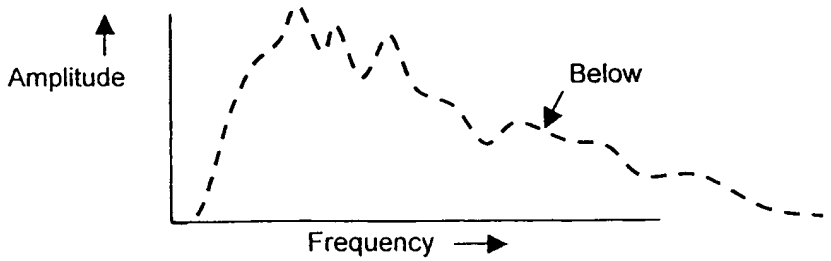

FIG 5

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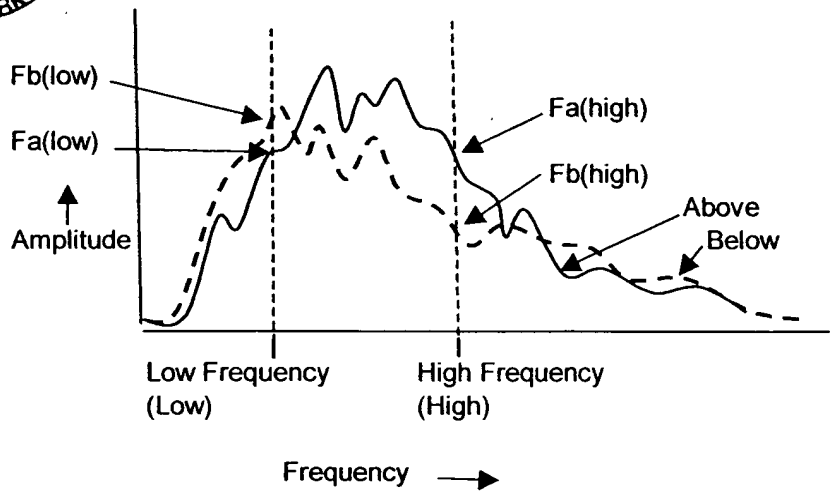


Six Measurements Obtained

Fa(high) High
Fa (low) Low
Fb(high)
Fb(low)

FIG 6

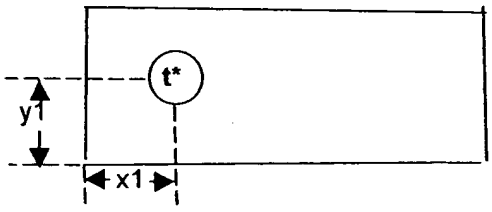
F high = Fa(high)/Fb(high)

F low = Fa(low)/Fb(low)

t* = [ln (F high) - ln (F low)]/(High - Low)

FIG 7

MAP OF FRACTURED ZONE



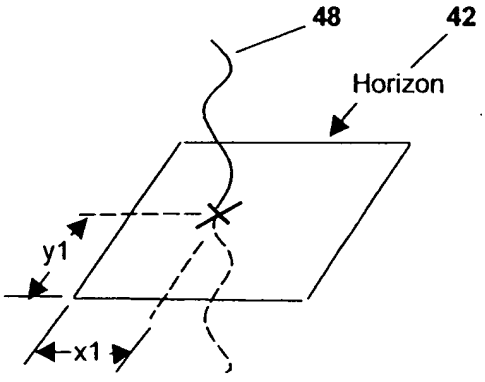


FIG 8

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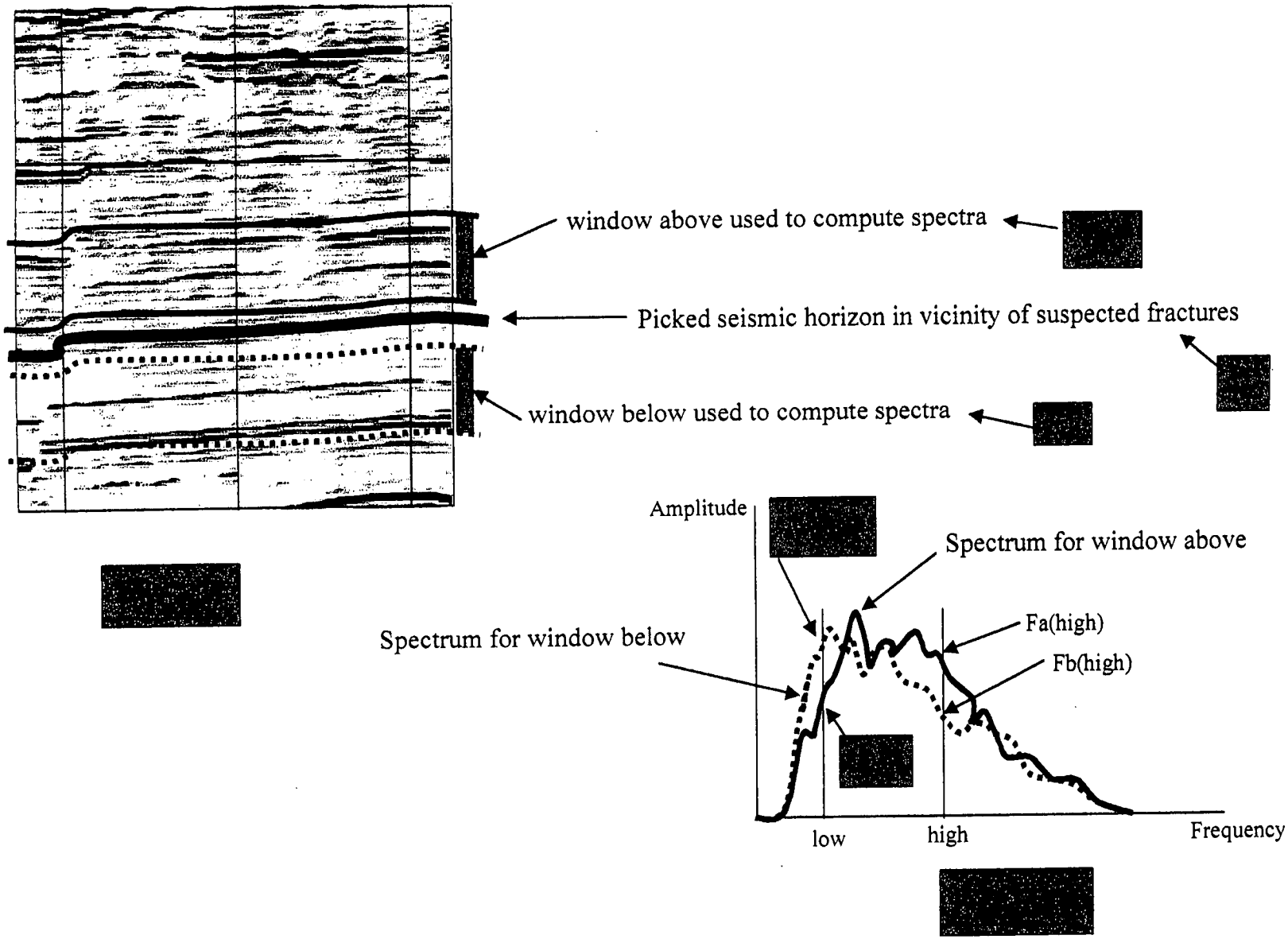

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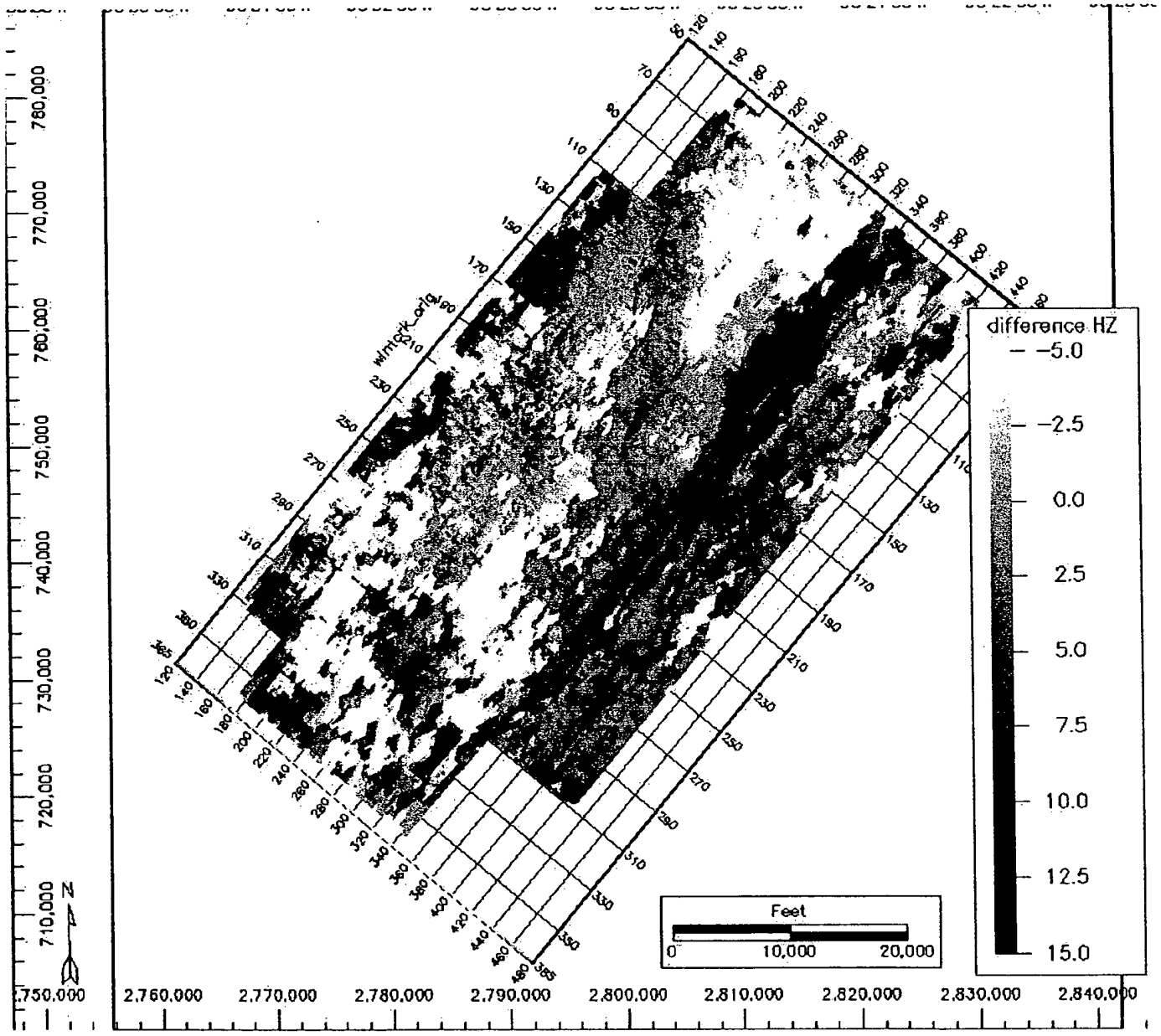

FIG. !!